A Unified User-Friendly Instrument Control and Data Acquisition System for the ORNL SANS Instrument Suite

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This supplemental information presents screenshots for various tabs in the new system.

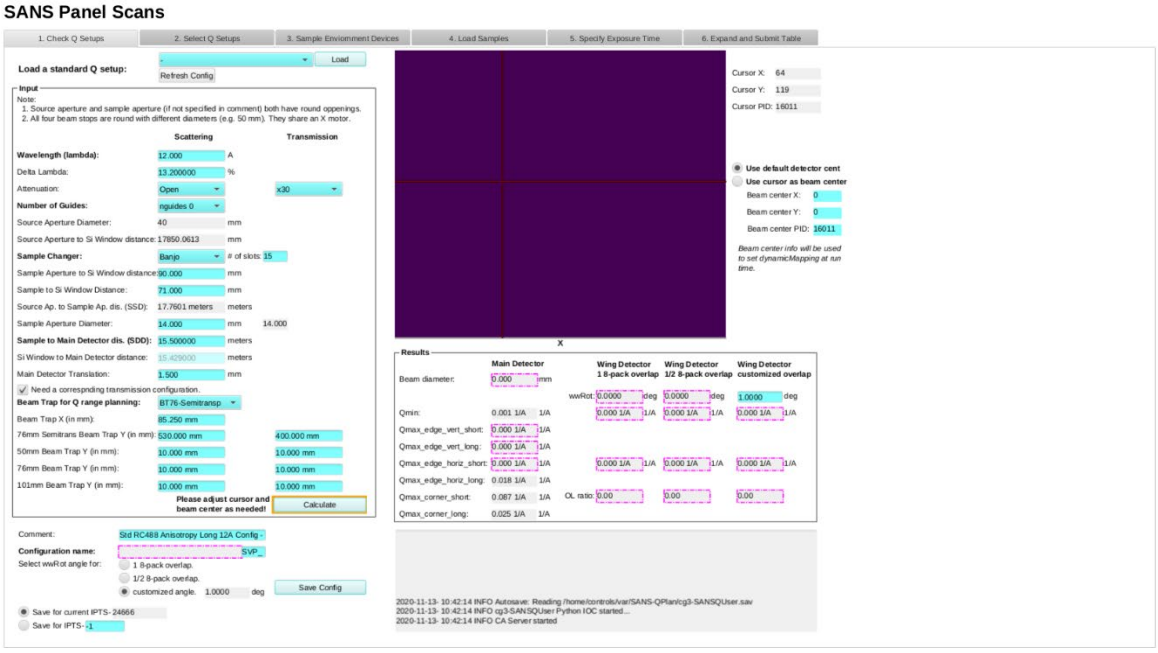

Fig. S1 Check Q Setups tab in the Panel Scans interface. The yellow outline highlights buttons that are required to be clicked to ensure the output parameters to be calculated.

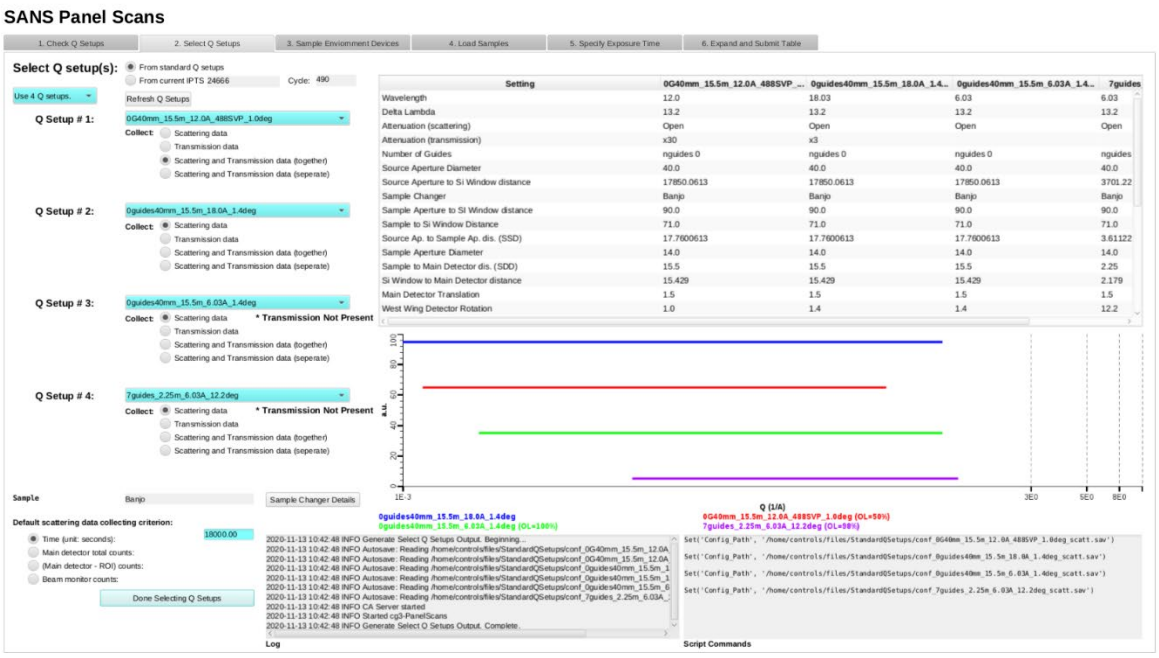

Fig. S2 Select Q Setups tab in the Panel Scans interface

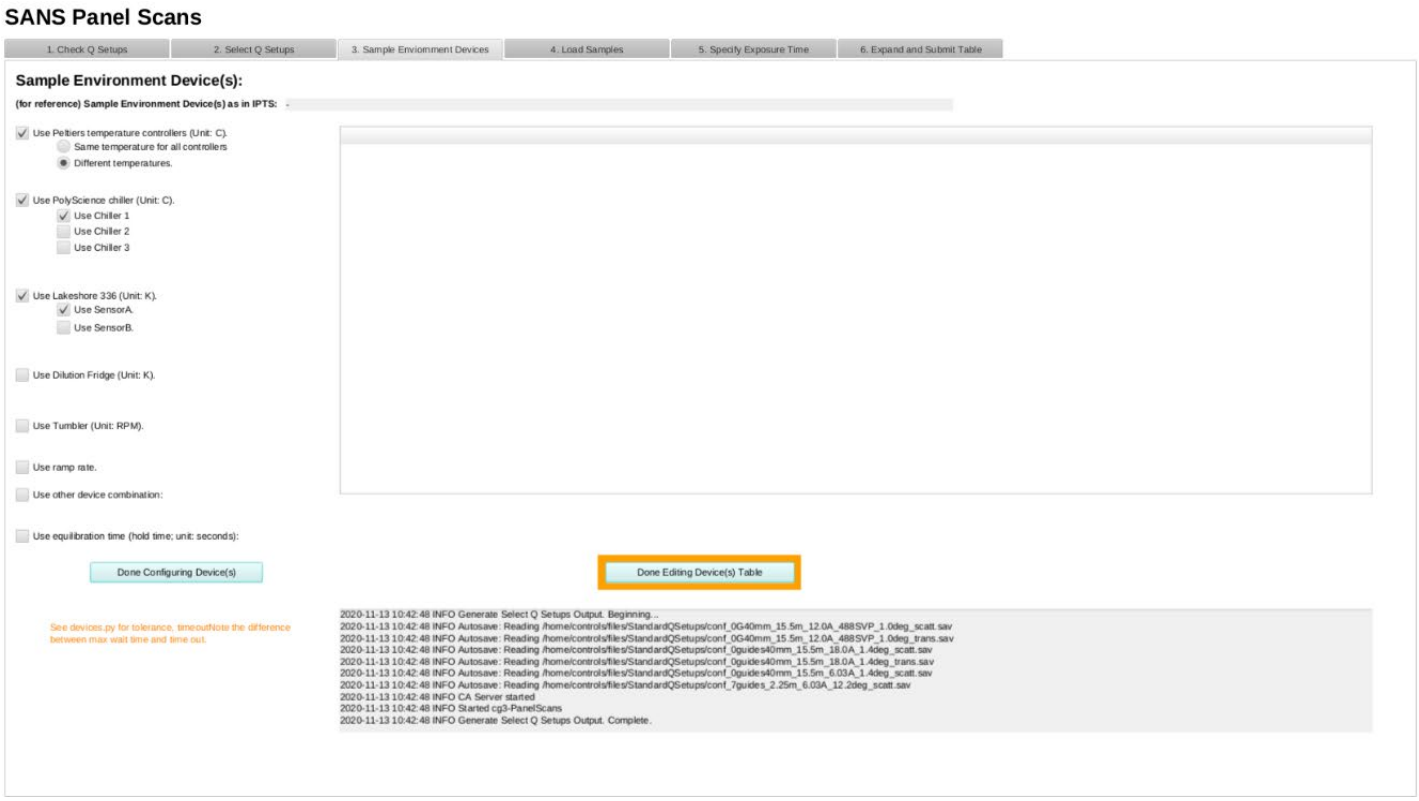

Fig. S3 Sample Environment Devices tab in the Panel Scans interface, for selecting specific sample environment for the current experiment. “Use other device combination:” will reveal the text input box to type a comma separated parameter names or aliases

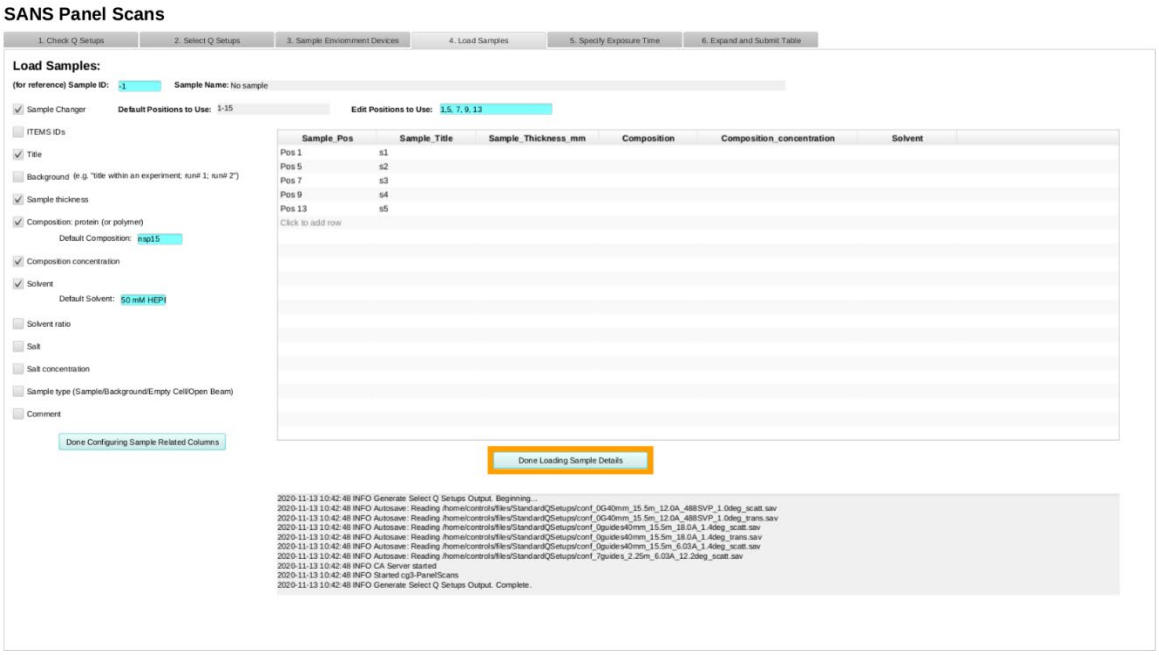

Fig. S4 Load Samples tab in the Panel Scans interface, for more specific sample information

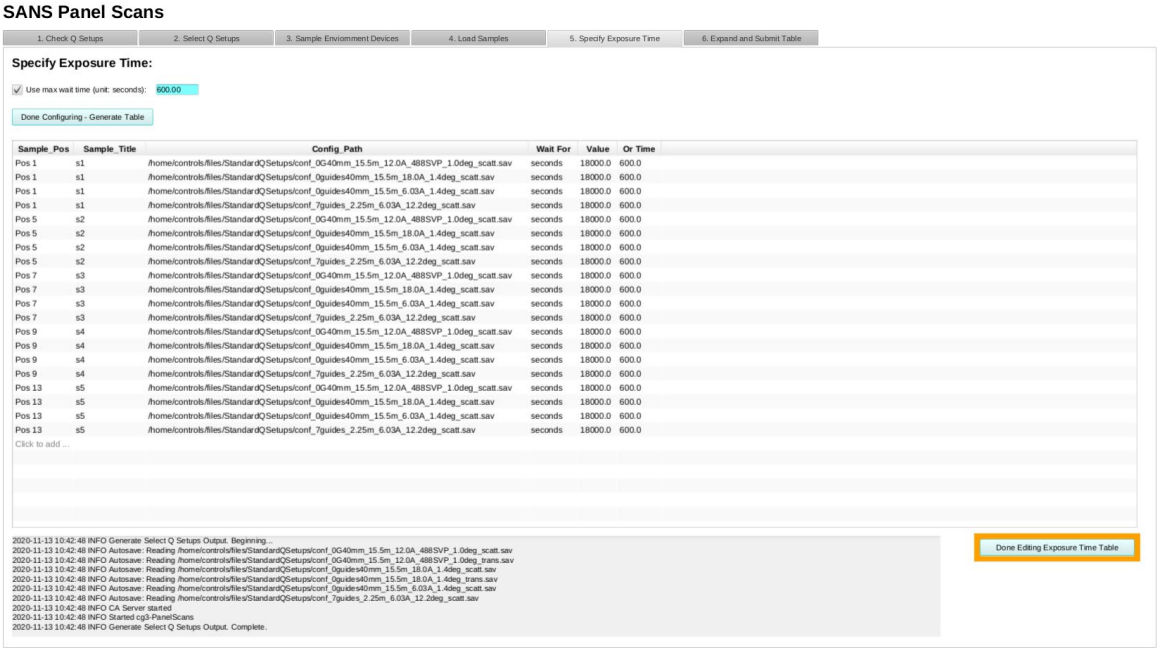

Fig. S5 Specify Exposure Time tab in the Panel Scans interface to setup measurement time or detector count at different configurations and samples

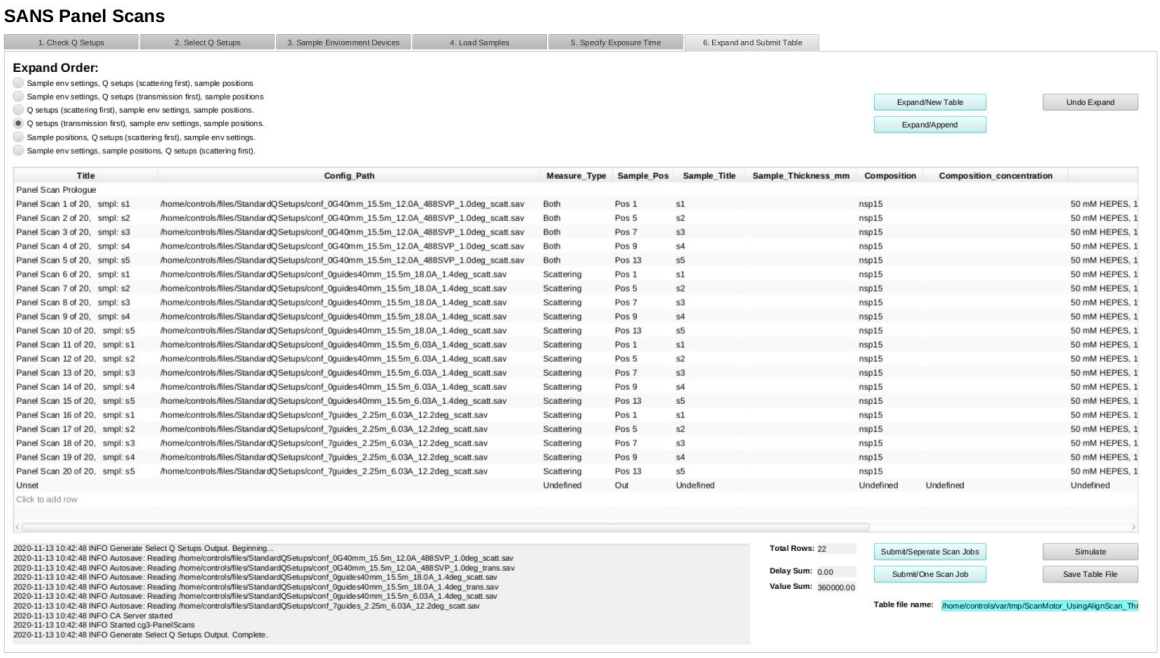

Fig. S6 Expand and Submit tab in the Panel Scans interface. It expands the scans in different ways with all conditions from previous setups (such as samples, sample environment, configurations, measurement type (transmission, scattering or both)), only part of the columns are shown in the screenshot

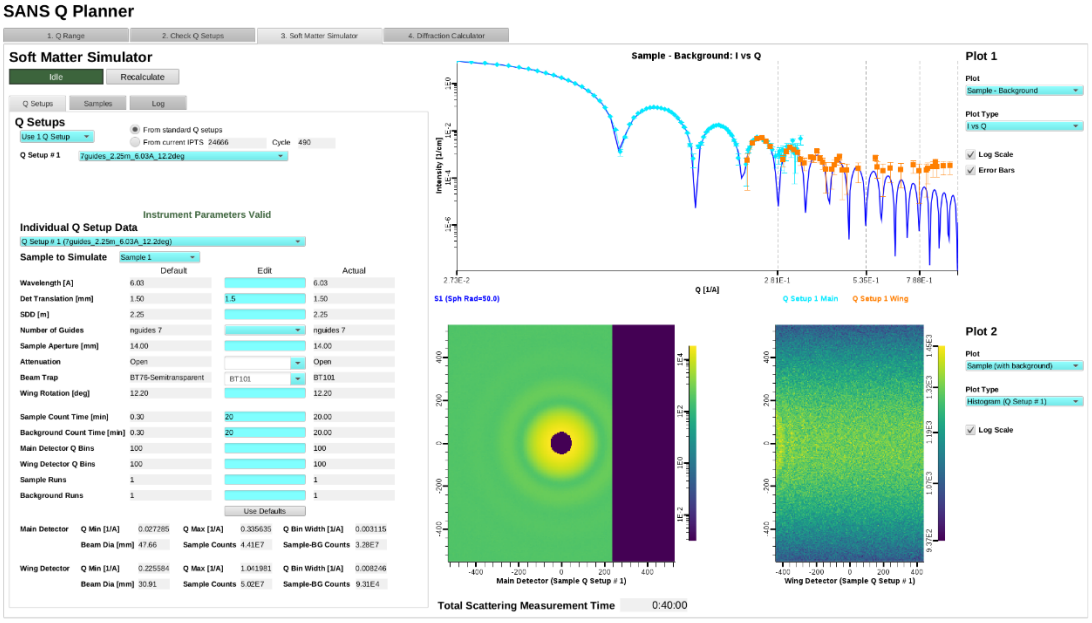

Fig. S7 The soft matter simulator with instrument specific parameters